



Welcome to [E-XFL.COM](https://www.e-xfl.com)

Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Obsolete
Number of LABs/CLBs	1452
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	113
Number of Gates	24000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	144-LQFP
Supplier Device Package	144-TQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a54sx16p-1tqg144i

Routing Resources

Clusters and SuperClusters can be connected through the use of two innovative local routing resources called *FastConnect* and *DirectConnect*, which enable extremely fast and predictable interconnection of modules within clusters and SuperClusters (Figure 1-5 and Figure 1-6). This routing architecture also dramatically reduces the number of antifuses required to complete a circuit, ensuring the highest possible performance.

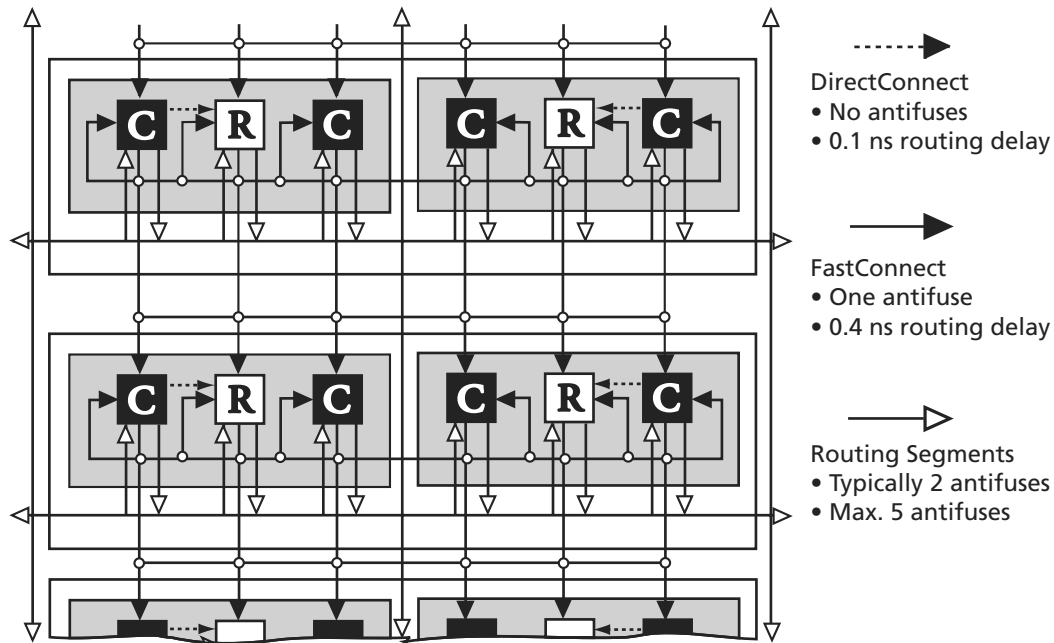


Figure 1-5 • DirectConnect and FastConnect for Type 1 SuperClusters

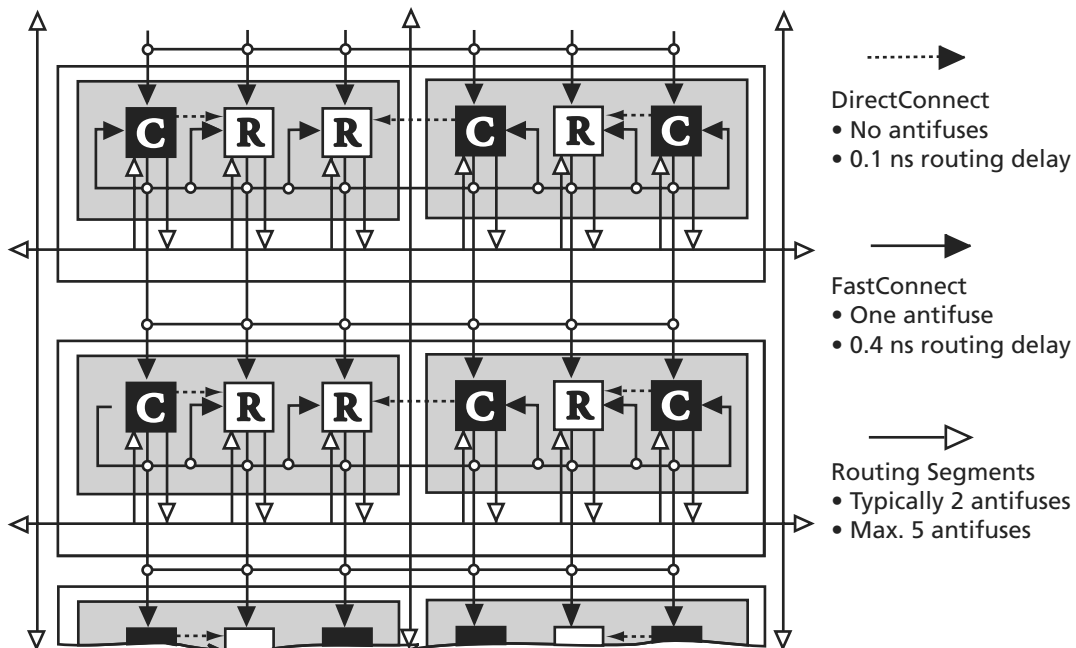


Figure 1-6 • DirectConnect and FastConnect for Type 2 SuperClusters

Boundary Scan Testing (BST)

All SX devices are IEEE 1149.1 compliant. SX devices offer superior diagnostic and testing capabilities by providing Boundary Scan Testing (BST) and probing capabilities. These functions are controlled through the special test pins in conjunction with the program fuse. The functionality of each pin is described in Table 1-2. In the dedicated test mode, TCK, TDI, and TDO are dedicated pins and cannot be used as regular I/Os. In flexible mode, TMS should be set HIGH through a pull-up resistor of 10 kΩ. TMS can be pulled LOW to initiate the test sequence.

The program fuse determines whether the device is in dedicated or flexible mode. The default (fuse not blown) is flexible mode.

Table 1-2 • Boundary Scan Pin Functionality

Program Fuse Blown (Dedicated Test Mode)	Program Fuse Not Blown (Flexible Mode)
TCK, TDI, TDO are dedicated BST pins.	TCK, TDI, TDO are flexible and may be used as I/Os.
No need for pull-up resistor for TMS	Use a pull-up resistor of 10 kΩ on TMS.

Dedicated Test Mode

In Dedicated mode, all JTAG pins are reserved for BST; designers cannot use them as regular I/Os. An internal pull-up resistor is automatically enabled on both TMS and TDI pins, and the TMS pin will function as defined in the IEEE 1149.1 (JTAG) specification.

To select Dedicated mode, users need to reserve the JTAG pins in Actel's Designer software by checking the "Reserve JTAG" box in "Device Selection Wizard" (Figure 1-7). JTAG pins comply with LVTTTL/TTL I/O specification regardless of whether they are used as a user I/O or a JTAG I/O. Refer to the Table 1-5 on page 1-8 for detailed specifications.

Development Tool Support

The SX family of FPGAs is fully supported by both the Actel Libero® Integrated Design Environment (IDE) and Designer FPGA Development software. Actel Libero IDE is a design management environment, seamlessly integrating design tools while guiding the user through the design flow, managing all design and log files, and passing necessary design data among tools. Libero IDE allows users to integrate both schematic and HDL synthesis into a single flow and verify the entire design in a single environment. Libero IDE includes Synplify® for Actel from Synplicity®, ViewDraw® for Actel from Mentor Graphics®, ModelSim® HDL Simulator from Mentor Graphics, WaveFormer Lite™ from SynaptiCAD™, and Designer software from Actel. Refer to the Libero IDE flow diagram (located on the Actel website) for more information.

Actel Designer software is a place-and-route tool and provides a comprehensive suite of backend support tools for FPGA development. The Designer software includes timing-driven place-and-route, and a world-class integrated static timing analyzer and constraints editor. With the Designer software, a user can select and lock package pins while only minimally impacting the results of place-and-route. Additionally, the back-annotation flow is compatible with all the major simulators, and the simulation results can be cross-probed with Silicon Explorer II, Actel integrated verification and logic analysis tool. Another tool included in the Designer software is the SmartGen core generator, which easily creates popular and commonly used logic functions for implementation into your schematic or HDL design. Actel Designer software is compatible with the most popular FPGA design entry and verification tools from companies such as Mentor Graphics, Synplicity, Synopsys®, and Cadence® Design Systems. The Designer software is available for both the Windows® and UNIX® operating systems.

Probe Circuit Control Pins

The Silicon Explorer II tool uses the boundary scan ports (TDI, TCK, TMS, and TDO) to select the desired nets for verification. The selected internal nets are assigned to the PRA/PRB pins for observation. Figure 1-8 on page 1-7 illustrates the interconnection between Silicon Explorer II and the FPGA to perform in-circuit verification.

Design Considerations

The TDI, TCK, TDO, PRA, and PRB pins should not be used as input or bidirectional ports. Because these pins are active during probing, critical signals input through these pins are not available while probing. In addition, the Security Fuse should not be programmed because doing so disables the Probe Circuitry.

Figure 1-7 • Device Selection Wizard

Table 1-4 • Recommended Operating Conditions

Parameter	Commercial	Industrial	Military	Units
Temperature Range*	0 to + 70	–40 to + 85	–55 to +125	°C
3.3 V Power Supply Tolerance	±10	±10	±10	%V _{CC}
5.0 V Power Supply Tolerance	±5	±10	±10	%V _{CC}

Note: *Ambient temperature (T_A) is used for commercial and industrial; case temperature (T_C) is used for military.

Table 1-5 • Electrical Specifications

Symbol	Parameter	Commercial		Industrial		Units
		Min.	Max.	Min.	Max.	
V _{OH}	(I _{OH} = –20 μ A) (CMOS) (I _{OH} = –8 mA) (TTL) (I _{OH} = –6 mA) (TTL)	(V _{CCI} – 0.1) 2.4	V _{CCI} V _{CCI}	(V _{CCI} – 0.1) 2.4	V _{CCI} V _{CCI}	V
V _{OL}	(I _{OL} = 20 μ A) (CMOS) (I _{OL} = 12 mA) (TTL) (I _{OL} = 8 mA) (TTL)		0.10 0.50		0.50	V
V _{IL}			0.8		0.8	V
V _{IH}		2.0		2.0		V
t _R , t _F	Input Transition Time t _R , t _F		50		50	ns
C _{IO}	C _{IO} I/O Capacitance		10		10	pF
I _{CC}	Standby Current, I _{CC}		4.0		4.0	mA
I _{CC(D)}	I _{CC(D)} I _{Dynamic} V _{CC} Supply Current	See "Evaluating Power in SX Devices" on page 1-16.				

Figure 1-9 shows the 5.0 V PCI V/I curve and the minimum and maximum PCI drive characteristics of the A54SX16P device.

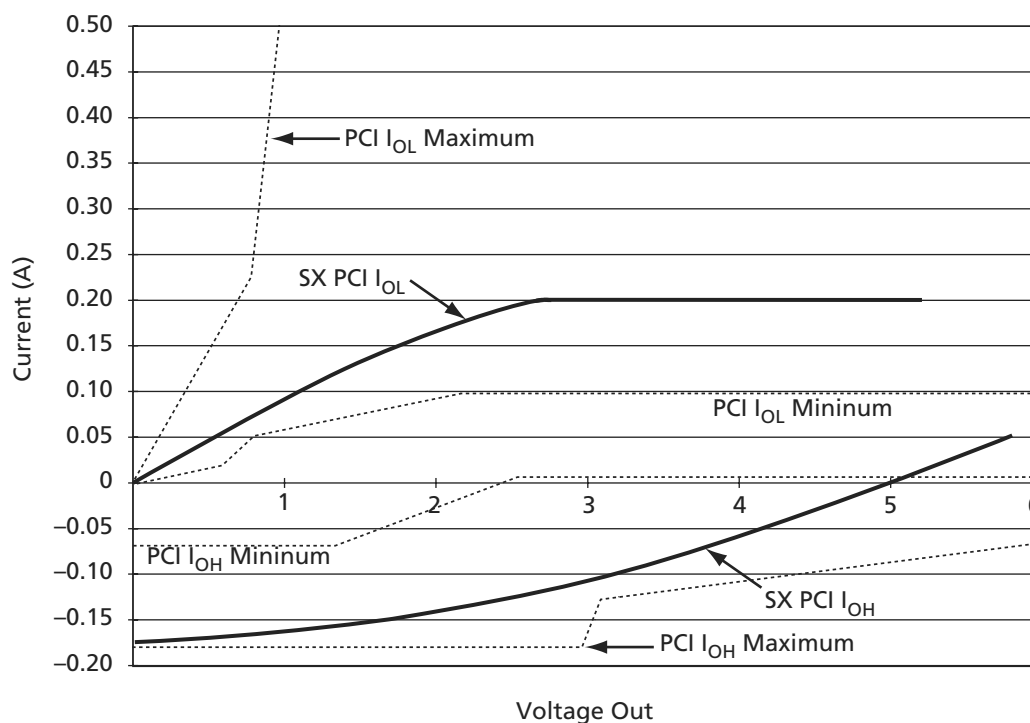


Figure 1-9 • **5.0 V PCI Curve for A54SX16P Device**

$$I_{OH} = 11.9 \times (V_{OUT} - 5.25) \times (V_{OUT} + 2.45)$$

for $V_{CC} > V_{OUT} > 3.1$ V

EQ 1-1

$$I_{OL} = 78.5 \times V_{OUT} \times (4.4 - V_{OUT})$$

for 0 V $< V_{OUT} < 0.71$ V

EQ 1-2

Power-Up Sequencing

Table 1-10 • Power-Up Sequencing

V _{CCA}	V _{CCR}	V _{CCI}	Power-Up Sequence	Comments
A54SX08, A54SX16, A54SX32				
3.3 V	5.0 V	3.3 V	5.0 V First 3.3 V Second	No possible damage to device
			3.3 V First 5.0 V Second	Possible damage to device
A54SX16P				
3.3 V	3.3 V	3.3 V	3.3 V Only	No possible damage to device
3.3 V	5.0 V	3.3 V	5.0 V First 3.3 V Second	No possible damage to device
			3.3 V First 5.0 V Second	Possible damage to device
3.3 V	5.0 V	5.0 V	5.0 V First 3.3 V Second	No possible damage to device
			3.3 V First 5.0 V Second	No possible damage to device

Note: No inputs should be driven (high or low) before completion of power-up.

Power-Down Sequencing

Table 1-11 • Power-Down Sequencing

V _{CCA}	V _{CCR}	V _{CCI}	Power-Down Sequence	Comments
A54SX08, A54SX16, A54SX32				
3.3 V	5.0 V	3.3 V	5.0 V First 3.3 V Second	Possible damage to device
			3.3 V First 5.0 V Second	No possible damage to device
A54SX16P				
3.3 V	3.3 V	3.3 V	3.3 V Only	No possible damage to device
3.3 V	5.0 V	3.3 V	5.0 V First 3.3 V Second	Possible damage to device
			3.3 V First 5.0 V Second	No possible damage to device
3.3 V	5.0 V	5.0 V	5.0 V First 3.3 V Second	No possible damage to device
			3.3 V First 5.0 V Second	No possible damage to device

Note: No inputs should be driven (high or low) after the beginning of the power-down sequence.

Evaluating Power in SX Devices

A critical element of system reliability is the ability of electronic devices to safely dissipate the heat generated during operation. The thermal characteristics of a circuit depend on the device and package used, the operating temperature, the operating current, and the system's ability to dissipate heat.

You should complete a power evaluation early in the design process to help identify potential heat-related problems in the system and to prevent the system from exceeding the device's maximum allowed junction temperature.

The actual power dissipated by most applications is significantly lower than the power the package can dissipate. However, a thermal analysis should be performed for all projects. To perform a power evaluation, follow these steps:

1. Estimate the power consumption of the application.
2. Calculate the maximum power allowed for the device and package.
3. Compare the estimated power and maximum power values.

Estimating Power Consumption

The total power dissipation for the SX family is the sum of the DC power dissipation and the AC power dissipation. Use EQ 1-5 to calculate the estimated power consumption of your application.

$$P_{\text{Total}} = P_{\text{DC}} + P_{\text{AC}}$$

EQ 1-5

DC Power Dissipation

The power due to standby current is typically a small component of the overall power. The Standby power is shown in Table 1-12 for commercial, worst-case conditions (70°C).

Table 1-12 • Standby Power

I _{CC}	V _{CC}	Power
4 mA	3.6 V	14.4 mW

The DC power dissipation is defined in EQ 1-6.

$$P_{\text{DC}} = (I_{\text{standby}}) \times V_{\text{CCA}} + (I_{\text{standby}}) \times V_{\text{CCR}} + (I_{\text{standby}}) \times V_{\text{CCI}} + xV_{\text{OL}} \times I_{\text{OL}} + y(V_{\text{CCI}} - V_{\text{OH}}) \times V_{\text{OH}}$$

EQ 1-6

AC Power Dissipation

The power dissipation of the SX Family is usually dominated by the dynamic power dissipation. Dynamic power dissipation is a function of frequency, equivalent capacitance, and power supply voltage. The AC power dissipation is defined in EQ 1-7 and EQ 1-8.

$$P_{\text{AC}} = P_{\text{Module}} + P_{\text{RCLKA Net}} + P_{\text{RCLKB Net}} + P_{\text{HCLK Net}} + P_{\text{Output Buffer}} + P_{\text{Input Buffer}}$$

EQ 1-7

$$P_{\text{AC}} = V_{\text{CCA}}^2 \times [(m \times C_{\text{EQM}} \times f_m)_{\text{Module}} + (n \times C_{\text{EQI}} \times f_n)_{\text{Input Buffer}} + (p \times (C_{\text{EQO}} + C_L) \times f_p)_{\text{Output Buffer}} + (0.5 \times (q_1 \times C_{\text{EQCR}} \times f_{q1}) + (r_1 \times f_{q1}))_{\text{RCLKA}} + (0.5 \times (q_2 \times C_{\text{EQCR}} \times f_{q2}) + (r_2 \times f_{q2}))_{\text{RCLKB}} + (0.5 \times (s_1 \times C_{\text{EQHV}} \times f_{s1}) + (C_{\text{EQHF}} \times f_{s1}))_{\text{HCLK}}]$$

EQ 1-8

Definition of Terms Used in Formula

- m = Number of logic modules switching at f_m
- n = Number of input buffers switching at f_n
- p = Number of output buffers switching at f_p
- q₁ = Number of clock loads on the first routed array clock
- q₂ = Number of clock loads on the second routed array clock
- x = Number of I/Os at logic low
- y = Number of I/Os at logic high
- r₁ = Fixed capacitance due to first routed array clock
- r₂ = Fixed capacitance due to second routed array clock
- s₁ = Number of clock loads on the dedicated array clock
- C_{EQM} = Equivalent capacitance of logic modules in pF
- C_{EQI} = Equivalent capacitance of input buffers in pF
- C_{EQO} = Equivalent capacitance of output buffers in pF
- C_{EQCR} = Equivalent capacitance of routed array clock in pF
- C_{EQHV} = Variable capacitance of dedicated array clock
- C_{EQHF} = Fixed capacitance of dedicated array clock
- C_L = Output lead capacitance in pF
- f_m = Average logic module switching rate in MHz
- f_n = Average input buffer switching rate in MHz
- f_p = Average output buffer switching rate in MHz
- f_{q1} = Average first routed array clock rate in MHz
- f_{q2} = Average second routed array clock rate in MHz
- f_{s1} = Average dedicated array clock rate in MHz

Table 1-13 shows capacitance values for various devices.

Table 1-13 • Capacitance Values for Devices

	A545X08	A545X16	A545X16P	A545X32
C _{EQM} (pF)	4.0	4.0	4.0	4.0
C _{EQI} (pF)	3.4	3.4	3.4	3.4
C _{EQO} (pF)	4.7	4.7	4.7	4.7
C _{EQCR} (pF)	1.6	1.6	1.6	1.6
C _{EQHV}	0.615	0.615	0.615	0.615
C _{EQHF}	60	96	96	140
r ₁ (pF)	87	138	138	171
r ₂ (pF)	87	138	138	171

Table 1-14 • Power Consumption Guidelines

Description	Power Consumption Guideline
Logic Modules (m)	20% of modules
Inputs Switching (n)	# inputs/4
Outputs Switching (p)	# outputs/4
First Routed Array Clock Loads (q ₁)	20% of register cells
Second Routed Array Clock Loads (q ₂)	20% of register cells
Load Capacitance (C _L)	35 pF
Average Logic Module Switching Rate (f _m)	f/10
Average Input Switching Rate (f _n)	f/5
Average Output Switching Rate (f _p)	f/10
Average First Routed Array Clock Rate (f _{q1})	f/2
Average Second Routed Array Clock Rate (f _{q2})	f/2
Average Dedicated Array Clock Rate (f _{s1})	f
Dedicated Clock Array Clock Loads (s ₁)	20% of regular modules

Follow the steps below to estimate power consumption. The values provided for the sample calculation below are for the shift register design above. This method for estimating power consumption is conservative and the actual power consumption of your design may be less than the estimated power consumption.

The total power dissipation for the SX family is the sum of the AC power dissipation and the DC power dissipation.

$$P_{\text{Total}} = P_{\text{AC}} (\text{dynamic power}) + P_{\text{DC}} (\text{static power})$$

EQ 1-9

Guidelines for Calculating Power Consumption

The power consumption guidelines are meant to represent worst-case scenarios so that they can be generally used to predict the upper limits of power dissipation. These guidelines are shown in Table 1-14.

Sample Power Calculation

One of the designs used to characterize the SX family was a 528 bit serial-in, serial-out shift register. The design utilized 100 percent of the dedicated flip-flops of an A545X16P device. A pattern of 0101... was clocked into the device at frequencies ranging from 1 MHz to 200 MHz. Shifting in a series of 0101... caused 50 percent of the flip-flops to toggle from low to high at every clock cycle.

AC Power Dissipation

$$P_{\text{AC}} = P_{\text{Module}} + P_{\text{RCLKA Net}} + P_{\text{RCLKB Net}} + P_{\text{HCLK Net}} + P_{\text{Output Buffer}} + P_{\text{Input Buffer}}$$

EQ 1-10

$$P_{\text{AC}} = V_{\text{CCA}}^2 \times [(m \times C_{\text{EQM}} \times f_m)_{\text{Module}} + (n \times C_{\text{EQI}} \times f_n)_{\text{Input Buffer}} + (p \times (C_{\text{EQO}} + C_L) \times f_p)_{\text{Output Buffer}} + (0.5 (q_1 \times C_{\text{EQCR}} \times f_{q1}) + (r_1 \times f_{q1}))_{\text{RCLKA}} + (0.5 (q_2 \times C_{\text{EQCR}} \times f_{q2}) + (r_2 \times f_{q2}))_{\text{RCLKB}} + (0.5 (s_1 \times C_{\text{EQHV}} \times f_{s1}) + (C_{\text{EQHF}} \times f_{s1}))_{\text{HCLK}}]$$

EQ 1-11

Table 1-17 • A54SX08 Timing Characteristics (Continued)

(Worst-Case Commercial Conditions, $V_{CCR} = 4.75\text{ V}$, $V_{CCA}, V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Network										
t _{HCKH}	Input LOW to HIGH (pad to R-Cell input)	1.0		1.1		1.3		1.5		ns
t _{HCKL}	Input HIGH to LOW (pad to R-Cell input)	1.0		1.2		1.4		1.6		ns
t _{HPWH}	Minimum Pulse Width HIGH	1.4		1.6		1.8		2.1		ns
t _{HPWL}	Minimum Pulse Width LOW	1.4		1.6		1.8		2.1		ns
t _{HCKSW}	Maximum Skew	0.1		0.2		0.2		0.2		ns
t _{HP}	Minimum Period	2.7		3.1		3.6		4.2		ns
f _{HMAX}	Maximum Frequency	350		320		280		240		MHz
Routed Array Clock Networks										
t _{RCKH}	Input LOW to HIGH (light load) (pad to R-Cell input)	1.3		1.5		1.7		2.0		ns
t _{RCKL}	Input HIGH to LOW (light load) (pad to R-Cell Input)	1.4		1.6		1.8		2.1		ns
t _{RCKH}	Input LOW to HIGH (50% load) (pad to R-Cell input)	1.4		1.7		1.9		2.2		ns
t _{RCKL}	Input HIGH to LOW (50% load) (pad to R-Cell input)	1.5		1.7		2.0		2.3		ns
t _{RCKH}	Input LOW to HIGH (100% load) (pad to R-Cell input)	1.5		1.7		1.9		2.2		ns
t _{RCKL}	Input HIGH to LOW (100% load) (pad to R-Cell input)	1.5		1.8		2.0		2.3		ns
t _{RPWH}	Min. Pulse Width HIGH	2.1		2.4		2.7		3.2		ns
t _{RPWL}	Min. Pulse Width LOW	2.1		2.4		2.7		3.2		ns
t _{RCKSW}	Maximum Skew (light load)	0.1		0.2		0.2		0.2		ns
t _{RCKSW}	Maximum Skew (50% load)	0.3		0.3		0.4		0.4		ns
t _{RCKSW}	Maximum Skew (100% load)	0.3		0.3		0.4		0.4		ns
TTL Output Module Timing ¹										
t _{DLH}	Data-to-Pad LOW to HIGH	1.6		1.9		2.1		2.5		ns
t _{DHL}	Data-to-Pad HIGH to LOW	1.6		1.9		2.1		2.5		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.1		2.4		2.8		3.2		ns
t _{ENZH}	Enable-to-Pad, Z to H	2.3		2.7		3.1		3.6		ns
t _{ENLZ}	Enable-to-Pad, L to Z	1.4		1.7		1.9		2.2		ns

Note:

- For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.

A54SX32 Timing Characteristics

Table 1-20 • A54SX32 Timing Characteristics
(Worst-Case Commercial Conditions, $V_{CCR} = 4.75\text{ V}$, $V_{CCA}, V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays ¹										
t _{PD}	Internal Array Module	0.6		0.7		0.8		0.9		ns
Predicted Routing Delays ²										
t _{DC}	FO = 1 Routing Delay, Direct Connect	0.1		0.1		0.1		0.1		ns
t _{FC}	FO = 1 Routing Delay, Fast Connect	0.3		0.4		0.4		0.5		ns
t _{RD1}	FO = 1 Routing Delay	0.3		0.4		0.4		0.5		ns
t _{RD2}	FO = 2 Routing Delay	0.7		0.8		0.9		1.0		ns
t _{RD3}	FO = 3 Routing Delay	1.0		1.2		1.4		1.6		ns
t _{RD4}	FO = 4 Routing Delay	1.4		1.6		1.8		2.1		ns
t _{RD8}	FO = 8 Routing Delay	2.7		3.1		3.5		4.1		ns
t _{RD12}	FO = 12 Routing Delay	4.0		4.7		5.3		6.2		ns
R-Cell Timing										
t _{RCO}	Sequential Clock-to-Q	0.8		1.1		1.3		1.4		ns
t _{CLR}	Asynchronous Clear-to-Q	0.5		0.6		0.7		0.8		ns
t _{PRESET}	Asynchronous Preset-to-Q	0.7		0.8		0.9		1.0		ns
t _{SUD}	Flip-Flop Data Input Set-Up	0.5		0.6		0.7		0.8		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	1.4		1.6		1.8		2.1		ns
Input Module Propagation Delays										
t _{INYH}	Input Data Pad-to-Y HIGH	1.5		1.7		1.9		2.2		ns
t _{INYL}	Input Data Pad-to-Y LOW	1.5		1.7		1.9		2.2		ns
Predicted Input Routing Delays ²										
t _{IRD1}	FO = 1 Routing Delay	0.3		0.4		0.4		0.5		ns
t _{IRD2}	FO = 2 Routing Delay	0.7		0.8		0.9		1.0		ns
t _{IRD3}	FO = 3 Routing Delay	1.0		1.2		1.4		1.6		ns
t _{IRD4}	FO = 4 Routing Delay	1.4		1.6		1.8		2.1		ns
t _{IRD8}	FO = 8 Routing Delay	2.7		3.1		3.5		4.1		ns
t _{IRD12}	FO = 12 Routing Delay	4.0		4.7		5.3		6.2		ns

Note:

- For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.
- Delays based on 35 pF loading, except t_{ENZL} and t_{ENZH} . For t_{ENZL} and t_{ENZH} the loading is 5 pF.

Package Pin Assignments

84-Pin PLCC

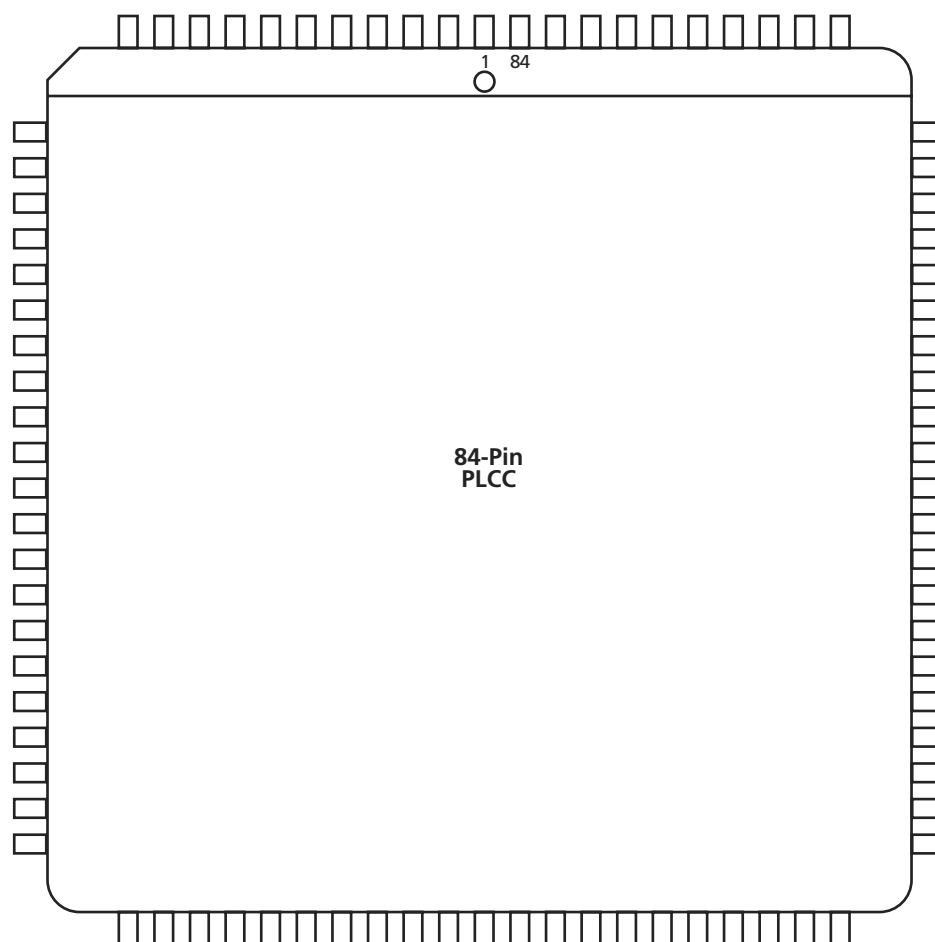


Figure 2-1 • 84-Pin PLCC (Top View)

Note

For Package Manufacturing and Environmental information, visit the Package Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

84-Pin PLCC	
Pin Number	A54SX08 Function
1	V _{CCR}
2	GND
3	V _{CCA}
4	PRA, I/O
5	I/O
6	I/O
7	V _{CCI}
8	I/O
9	I/O
10	I/O
11	TCK, I/O
12	TDI, I/O
13	I/O
14	I/O
15	I/O
16	TMS
17	I/O
18	I/O
19	I/O
20	I/O
21	I/O
22	I/O
23	I/O
24	I/O
25	I/O
26	I/O
27	GND
28	V _{CCI}
29	I/O
30	I/O
31	I/O
32	I/O
33	I/O
34	I/O
35	I/O

84-Pin PLCC	
Pin Number	A54SX08 Function
36	I/O
37	I/O
38	I/O
39	I/O
40	PRB, I/O
41	V _{CCA}
42	GND
43	V _{CCR}
44	I/O
45	HCLK
46	I/O
47	I/O
48	I/O
49	I/O
50	I/O
51	I/O
52	TDO, I/O
53	I/O
54	I/O
55	I/O
56	I/O
57	I/O
58	I/O
59	V _{CCA}
60	V _{CCI}
61	GND
62	I/O
63	I/O
64	I/O
65	I/O
66	I/O
67	I/O
68	V _{CCA}
69	GND
70	I/O

84-Pin PLCC	
Pin Number	A54SX08 Function
71	I/O
72	I/O
73	I/O
74	I/O
75	I/O
76	I/O
77	I/O
78	I/O
79	I/O
80	I/O
81	I/O
82	I/O
83	CLKA
84	CLKB

208-Pin PQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
1	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O
3	I/O	I/O	I/O
4	NC	I/O	I/O
5	I/O	I/O	I/O
6	NC	I/O	I/O
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	I/O	I/O	I/O
10	I/O	I/O	I/O
11	TMS	TMS	TMS
12	V _{CCI}	V _{CCI}	V _{CCI}
13	I/O	I/O	I/O
14	NC	I/O	I/O
15	I/O	I/O	I/O
16	I/O	I/O	I/O
17	NC	I/O	I/O
18	I/O	I/O	I/O
19	I/O	I/O	I/O
20	NC	I/O	I/O
21	I/O	I/O	I/O
22	I/O	I/O	I/O
23	NC	I/O	I/O
24	I/O	I/O	I/O
25	V _{CCR}	V _{CCR}	V _{CCR}
26	GND	GND	GND
27	V _{CCA}	V _{CCA}	V _{CCA}
28	GND	GND	GND
29	I/O	I/O	I/O
30	I/O	I/O	I/O
31	NC	I/O	I/O
32	I/O	I/O	I/O
33	I/O	I/O	I/O
34	I/O	I/O	I/O
35	NC	I/O	I/O
36	I/O	I/O	I/O

208-Pin PQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
37	I/O	I/O	I/O
38	I/O	I/O	I/O
39	NC	I/O	I/O
40	V _{CCI}	V _{CCI}	V _{CCI}
41	V _{CCA}	V _{CCA}	V _{CCA}
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	I/O	I/O	I/O
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	NC	I/O	I/O
49	I/O	I/O	I/O
50	NC	I/O	I/O
51	I/O	I/O	I/O
52	GND	GND	GND
53	I/O	I/O	I/O
54	I/O	I/O	I/O
55	I/O	I/O	I/O
56	I/O	I/O	I/O
57	I/O	I/O	I/O
58	I/O	I/O	I/O
59	I/O	I/O	I/O
60	V _{CCI}	V _{CCI}	V _{CCI}
61	NC	I/O	I/O
62	I/O	I/O	I/O
63	I/O	I/O	I/O
64	NC	I/O	I/O
65*	I/O	I/O	NC*
66	I/O	I/O	I/O
67	NC	I/O	I/O
68	I/O	I/O	I/O
69	I/O	I/O	I/O
70	NC	I/O	I/O
71	I/O	I/O	I/O
72	I/O	I/O	I/O

Note: * Note that Pin 65 in the A54SX32—PQ208 is a no connect (NC).

144-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16P Function	A54SX32 Function
1	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O
3	I/O	I/O	I/O
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	TMS	TMS	TMS
10	V _{CCI}	V _{CCI}	V _{CCI}
11	GND	GND	GND
12	I/O	I/O	I/O
13	I/O	I/O	I/O
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	I/O	I/O	I/O
17	I/O	I/O	I/O
18	I/O	I/O	I/O
19	V _{CCR}	V _{CCR}	V _{CCR}
20	V _{CCA}	V _{CCA}	V _{CCA}
21	I/O	I/O	I/O
22	I/O	I/O	I/O
23	I/O	I/O	I/O
24	I/O	I/O	I/O
25	I/O	I/O	I/O
26	I/O	I/O	I/O
27	I/O	I/O	I/O
28	GND	GND	GND
29	V _{CCI}	V _{CCI}	V _{CCI}
30	V _{CCA}	V _{CCA}	V _{CCA}
31	I/O	I/O	I/O
32	I/O	I/O	I/O
33	I/O	I/O	I/O
34	I/O	I/O	I/O
35	I/O	I/O	I/O
36	GND	GND	GND

144-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16P Function	A54SX32 Function
37	I/O	I/O	I/O
38	I/O	I/O	I/O
39	I/O	I/O	I/O
40	I/O	I/O	I/O
41	I/O	I/O	I/O
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	V _{CCI}	V _{CCI}	V _{CCI}
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	I/O	I/O	I/O
50	I/O	I/O	I/O
51	I/O	I/O	I/O
52	I/O	I/O	I/O
53	I/O	I/O	I/O
54	PRB, I/O	PRB, I/O	PRB, I/O
55	I/O	I/O	I/O
56	V _{CCA}	V _{CCA}	V _{CCA}
57	GND	GND	GND
58	V _{CCR}	V _{CCR}	V _{CCR}
59	I/O	I/O	I/O
60	HCLK	HCLK	HCLK
61	I/O	I/O	I/O
62	I/O	I/O	I/O
63	I/O	I/O	I/O
64	I/O	I/O	I/O
65	I/O	I/O	I/O
66	I/O	I/O	I/O
67	I/O	I/O	I/O
68	V _{CCI}	V _{CCI}	V _{CCI}
69	I/O	I/O	I/O
70	I/O	I/O	I/O
71	TDO, I/O	TDO, I/O	TDO, I/O
72	I/O	I/O	I/O

176-Pin TQFP

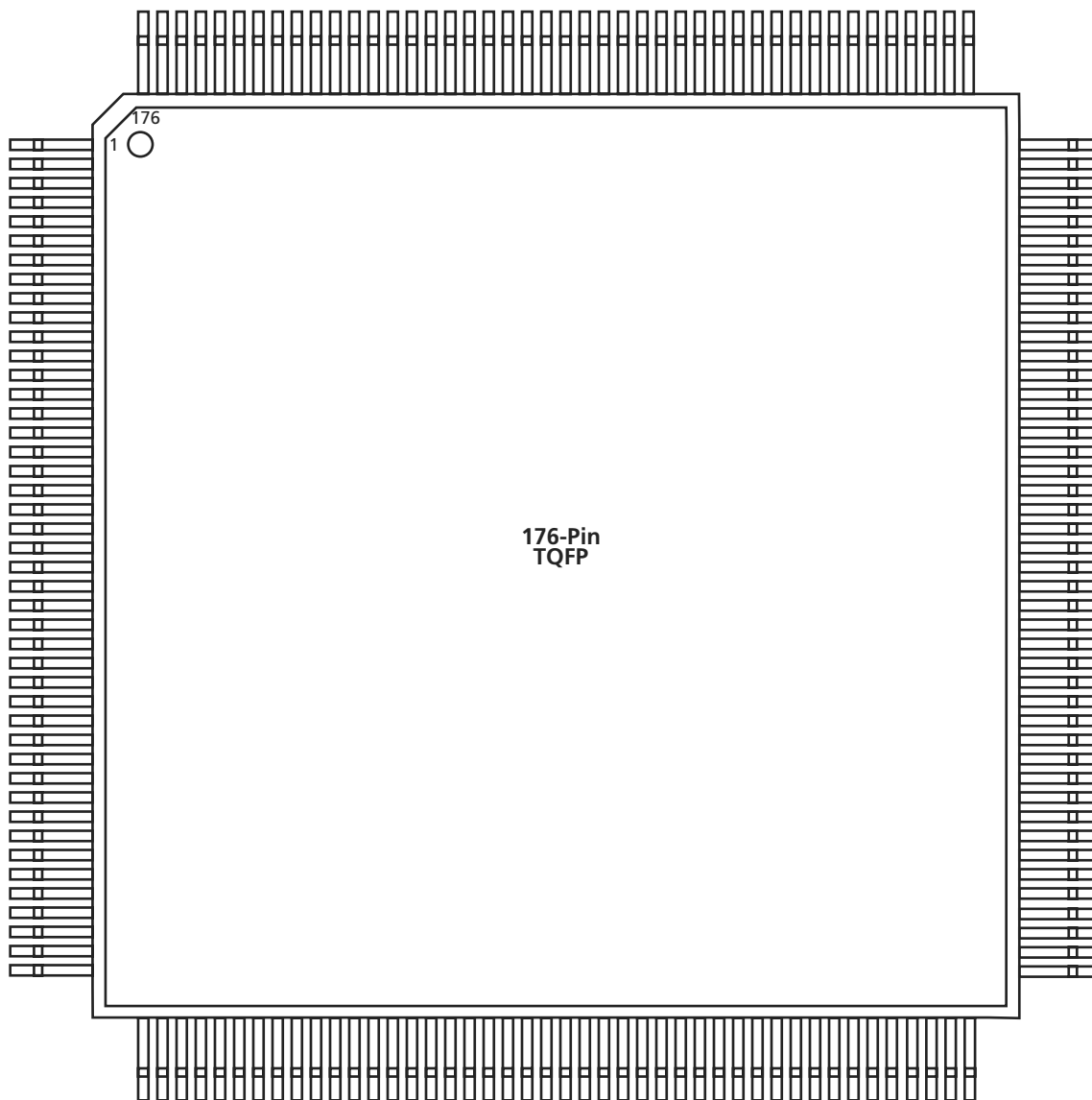


Figure 2-4 • 176-Pin TQFP (Top View)

Note

For Package Manufacturing and Environmental information, visit the Package Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

176-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
1	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O
3	NC	I/O	I/O
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	I/O	I/O	I/O
10	TMS	TMS	TMS
11	V _{CCI}	V _{CCI}	V _{CCI}
12	NC	I/O	I/O
13	I/O	I/O	I/O
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	I/O	I/O	I/O
17	I/O	I/O	I/O
18	I/O	I/O	I/O
19	I/O	I/O	I/O
20	I/O	I/O	I/O
21	GND	GND	GND
22	V _{CCA}	V _{CCA}	V _{CCA}
23	GND	GND	GND
24	I/O	I/O	I/O
25	I/O	I/O	I/O
26	I/O	I/O	I/O
27	I/O	I/O	I/O
28	I/O	I/O	I/O
29	I/O	I/O	I/O
30	I/O	I/O	I/O
31	I/O	I/O	I/O
32	V _{CCI}	V _{CCI}	V _{CCI}
33	V _{CCA}	V _{CCA}	V _{CCA}
34	I/O	I/O	I/O

176-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
35	I/O	I/O	I/O
36	I/O	I/O	I/O
37	I/O	I/O	I/O
38	I/O	I/O	I/O
39	I/O	I/O	I/O
40	NC	I/O	I/O
41	I/O	I/O	I/O
42	NC	I/O	I/O
43	I/O	I/O	I/O
44	GND	GND	GND
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	I/O	I/O	I/O
50	I/O	I/O	I/O
51	I/O	I/O	I/O
52	V _{CCI}	V _{CCI}	V _{CCI}
53	I/O	I/O	I/O
54	NC	I/O	I/O
55	I/O	I/O	I/O
56	I/O	I/O	I/O
57	NC	I/O	I/O
58	I/O	I/O	I/O
59	I/O	I/O	I/O
60	I/O	I/O	I/O
61	I/O	I/O	I/O
62	I/O	I/O	I/O
63	I/O	I/O	I/O
64	PRB, I/O	PRB, I/O	PRB, I/O
65	GND	GND	GND
66	V _{CCA}	V _{CCA}	V _{CCA}
67	V _{CCR}	V _{CCR}	V _{CCR}
68	I/O	I/O	I/O

176-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
69	HCLK	HCLK	HCLK
70	I/O	I/O	I/O
71	I/O	I/O	I/O
72	I/O	I/O	I/O
73	I/O	I/O	I/O
74	I/O	I/O	I/O
75	I/O	I/O	I/O
76	I/O	I/O	I/O
77	I/O	I/O	I/O
78	I/O	I/O	I/O
79	NC	I/O	I/O
80	I/O	I/O	I/O
81	NC	I/O	I/O
82	V _{CCI}	V _{CCI}	V _{CCI}
83	I/O	I/O	I/O
84	I/O	I/O	I/O
85	I/O	I/O	I/O
86	I/O	I/O	I/O
87	TDO, I/O	TDO, I/O	TDO, I/O
88	I/O	I/O	I/O
89	GND	GND	GND
90	NC	I/O	I/O
91	NC	I/O	I/O
92	I/O	I/O	I/O
93	I/O	I/O	I/O
94	I/O	I/O	I/O
95	I/O	I/O	I/O
96	I/O	I/O	I/O
97	I/O	I/O	I/O
98	V _{CCA}	V _{CCA}	V _{CCA}
99	V _{CCI}	V _{CCI}	V _{CCI}
100	I/O	I/O	I/O
101	I/O	I/O	I/O
102	I/O	I/O	I/O

176-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
103	I/O	I/O	I/O
104	I/O	I/O	I/O
105	I/O	I/O	I/O
106	I/O	I/O	I/O
107	I/O	I/O	I/O
108	GND	GND	GND
109	V _{CCA}	V _{CCA}	V _{CCA}
110	GND	GND	GND
111	I/O	I/O	I/O
112	I/O	I/O	I/O
113	I/O	I/O	I/O
114	I/O	I/O	I/O
115	I/O	I/O	I/O
116	I/O	I/O	I/O
117	I/O	I/O	I/O
118	NC	I/O	I/O
119	I/O	I/O	I/O
120	NC	I/O	I/O
121	NC	I/O	I/O
122	V _{CCA}	V _{CCA}	V _{CCA}
123	GND	GND	GND
124	V _{CCI}	V _{CCI}	V _{CCI}
125	I/O	I/O	I/O
126	I/O	I/O	I/O
127	I/O	I/O	I/O
128	I/O	I/O	I/O
129	I/O	I/O	I/O
130	I/O	I/O	I/O
131	NC	I/O	I/O
132	NC	I/O	I/O
133	GND	GND	GND
134	I/O	I/O	I/O
135	I/O	I/O	I/O
136	I/O	I/O	I/O

100-Pin VQFP		
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function
1	GND	GND
2	TDI, I/O	TDI, I/O
3	I/O	I/O
4	I/O	I/O
5	I/O	I/O
6	I/O	I/O
7	TMS	TMS
8	V _{CCI}	V _{CCI}
9	GND	GND
10	I/O	I/O
11	I/O	I/O
12	I/O	I/O
13	I/O	I/O
14	I/O	I/O
15	I/O	I/O
16	I/O	I/O
17	I/O	I/O
18	I/O	I/O
19	I/O	I/O
20	V _{CCI}	V _{CCI}
21	I/O	I/O
22	I/O	I/O
23	I/O	I/O
24	I/O	I/O
25	I/O	I/O
26	I/O	I/O
27	I/O	I/O
28	I/O	I/O
29	I/O	I/O
30	I/O	I/O
31	I/O	I/O
32	I/O	I/O
33	I/O	I/O
34	PRB, I/O	PRB, I/O

100-Pin VQFP		
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function
35	V _{CCA}	V _{CCA}
36	GND	GND
37	V _{CCR}	V _{CCR}
38	I/O	I/O
39	HCLK	HCLK
40	I/O	I/O
41	I/O	I/O
42	I/O	I/O
43	I/O	I/O
44	V _{CCI}	V _{CCI}
45	I/O	I/O
46	I/O	I/O
47	I/O	I/O
48	I/O	I/O
49	TDO, I/O	TDO, I/O
50	I/O	I/O
51	GND	GND
52	I/O	I/O
53	I/O	I/O
54	I/O	I/O
55	I/O	I/O
56	I/O	I/O
57	V _{CCA}	V _{CCA}
58	V _{CCI}	V _{CCI}
59	I/O	I/O
60	I/O	I/O
61	I/O	I/O
62	I/O	I/O
63	I/O	I/O
64	I/O	I/O
65	I/O	I/O
66	I/O	I/O
67	V _{CCA}	V _{CCA}
68	GND	GND

100-Pin VQFP		
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function
69	GND	GND
70	I/O	I/O
71	I/O	I/O
72	I/O	I/O
73	I/O	I/O
74	I/O	I/O
75	I/O	I/O
76	I/O	I/O
77	I/O	I/O
78	I/O	I/O
79	I/O	I/O
80	I/O	I/O
81	I/O	I/O
82	V _{CCI}	V _{CCI}
83	I/O	I/O
84	I/O	I/O
85	I/O	I/O
86	I/O	I/O
87	CLKA	CLKA
88	CLKB	CLKB
89	V _{CCR}	V _{CCR}
90	V _{CCA}	V _{CCA}
91	GND	GND
92	PRA, I/O	PRA, I/O
93	I/O	I/O
94	I/O	I/O
95	I/O	I/O
96	I/O	I/O
97	I/O	I/O
98	I/O	I/O
99	I/O	I/O
100	TCK, I/O	TCK, I/O

144-Pin FBGA		144-Pin FBGA		144-Pin FBGA		144-Pin FBGA	
Pin Number	A54SX08 Function	Pin Number	A54SX08 Function	Pin Number	A54SX08 Function	Pin Number	A54SX08 Function
A1	I/O	D1	I/O	G1	I/O	K1	I/O
A2	I/O	D2	V _{CCI}	G2	GND	K2	I/O
A3	I/O	D3	TDI, I/O	G3	I/O	K3	I/O
A4	I/O	D4	I/O	G4	I/O	K4	I/O
A5	V _{CCA}	D5	I/O	G5	GND	K5	I/O
A6	GND	D6	I/O	G6	GND	K6	I/O
A7	CLKA	D7	I/O	G7	GND	K7	GND
A8	I/O	D8	I/O	G8	V _{CCI}	K8	I/O
A9	I/O	D9	I/O	G9	I/O	K9	I/O
A10	I/O	D10	I/O	G10	I/O	K10	GND
A11	I/O	D11	I/O	G11	I/O	K11	I/O
A12	I/O	D12	I/O	G12	I/O	K12	I/O
B1	I/O	E1	I/O	H1	I/O	L1	GND
B2	GND	E2	I/O	H2	I/O	L2	I/O
B3	I/O	E3	I/O	H3	I/O	L3	I/O
B4	I/O	E4	I/O	H4	I/O	L4	I/O
B5	I/O	E5	TMS	H5	V _{CCA}	L5	I/O
B6	I/O	E6	V _{CCI}	H6	V _{CCA}	L6	I/O
B7	CLKB	E7	V _{CCI}	H7	V _{CCI}	L7	HCLK
B8	I/O	E8	V _{CCI}	H8	V _{CCI}	L8	I/O
B9	I/O	E9	V _{CCA}	H9	V _{CCA}	L9	I/O
B10	I/O	E10	I/O	H10	I/O	L10	I/O
B11	GND	E11	GND	H11	I/O	L11	I/O
B12	I/O	E12	I/O	H12	V _{CCR}	L12	I/O
C1	I/O	F1	I/O	J1	I/O	M1	I/O
C2	I/O	F2	I/O	J2	I/O	M2	I/O
C3	TCK, I/O	F3	V _{CCR}	J3	I/O	M3	I/O
C4	I/O	F4	I/O	J4	I/O	M4	I/O
C5	I/O	F5	GND	J5	I/O	M5	I/O
C6	PRA, I/O	F6	GND	J6	PRB, I/O	M6	I/O
C7	I/O	F7	GND	J7	I/O	M7	V _{CCA}
C8	I/O	F8	V _{CCI}	J8	I/O	M8	I/O
C9	I/O	F9	I/O	J9	I/O	M9	I/O
C10	I/O	F10	GND	J10	I/O	M10	I/O
C11	I/O	F11	I/O	J11	I/O	M11	TDO, I/O
C12	I/O	F12	I/O	J12	V _{CCA}	M12	I/O

Datasheet Information

List of Changes

The following table lists critical changes that were made in the current version of the document.

Previous Version	Changes in Current Version (v3.2)	Page
v3.1 (June 2003)	The "Ordering Information" was updated to include RoHS information.	1-ii
	The Product Plan was removed since all products have been released.	N/A
	Information concerning the TRST pin in the "Probe Circuit Control Pins" section was removed.	1-6
	The "Dedicated Test Mode" section is new.	1-6
	The "Programming" section is new.	1-7
	A note was added to the "Power-Up Sequencing" table.	1-15
	A note was added to the "Power-Down Sequencing" table. The 3.3 V comments were updated for the following devices: A545X08, A545X16, A545X32.	1-15
	U11 and U13 were added to the "313-Pin PBGA" table.	2-17
v3.0.1	Storage temperature in Table 1-3 was updated.	1-7
	Table 1-1 was updated.	1-5

Datasheet Categories

In order to provide the latest information to designers, some datasheets are published before data has been fully characterized. Datasheets are designated as "Product Brief," "Advanced," "Production," and "Datasheet Supplement." The definitions of these categories are as follows:

Product Brief

The product brief is a summarized version of a datasheet (advanced or production) containing general product information. This brief gives an overview of specific device and family information.

Advanced

This datasheet version contains initial estimated information based on simulation, other products, devices, or speed grades. This information can be used as estimates, but not for production.

Unmarked (production)

This datasheet version contains information that is considered to be final.

Datasheet Supplement

The datasheet supplement gives specific device information for a derivative family that differs from the general family datasheet. The supplement is to be used in conjunction with the datasheet to obtain more detailed information and for specifications that do not differ between the two families.

International Traffic in Arms Regulations (ITAR) and Export Administration Regulations (EAR)

The products described in this datasheet are subject to the International Traffic in Arms Regulations (ITAR) or the Export Administration Regulations (EAR). They may require an approved export license prior to their export. An export can include a release or disclosure to a foreign national inside or outside the United States.